## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination NAKANO ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,128,461	10-2000	Yoshikawa, Tadanobu	399/350
*	В	US-2002/0057927	05-2002	Kobayashi et al.	399/159
	С	US-			
	D	US-			
	Ε	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Ρ					
	σ					
	R					
	S					
	Τ					

## **NON-PATENT DOCUMENTS**

*	T	College Advantage Date Delicher Edition (Notice Delicher Delicher)
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	,
	>	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.